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(12) **United States Design Patent**
Matoba et al.

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- (54) **ELECTRON MICROSCOPE**
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- (**) Term: **14 Years**
- (21) Appl. No.: **29/456,320**
- (22) Filed: **May 30, 2013**
- (30) **Foreign Application Priority Data**

Nov. 30, 2012 (JP) 2012-029392

- (51) **LOC (10) Cl.** **16-01**
- (52) **U.S. Cl.**

CPC **H01J 37/26 (2013.01)**
USPC **D16/131**

- (58) **Field of Classification Search**
 - CPC H01J 37/26
 - USPC D16/131, 130; 250/310, 311, 440.11;
D24/216, 232; D10/81; 422/63, 66;
248/636, 550
- See application file for complete search history.

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- (57) **CLAIM**

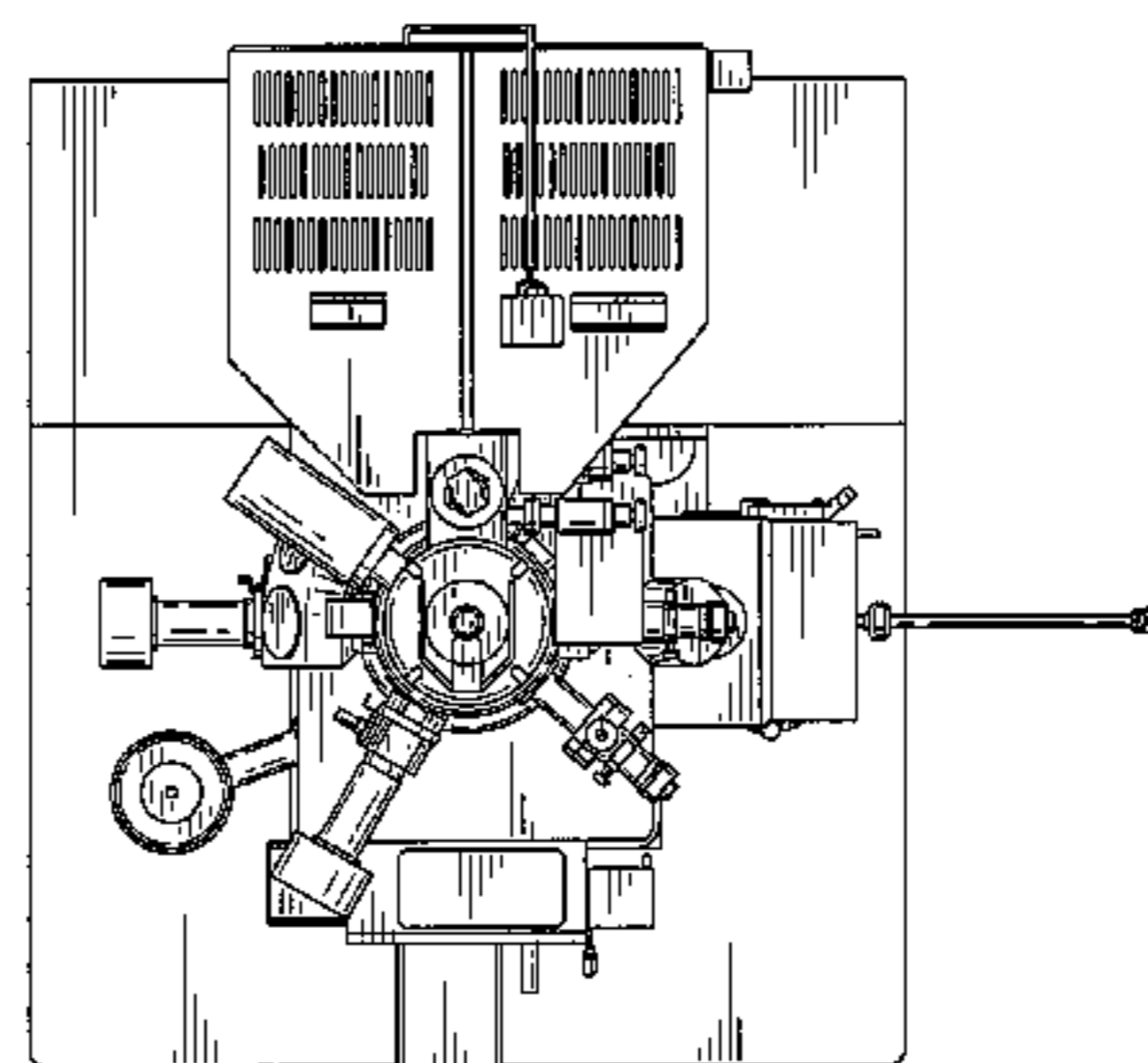
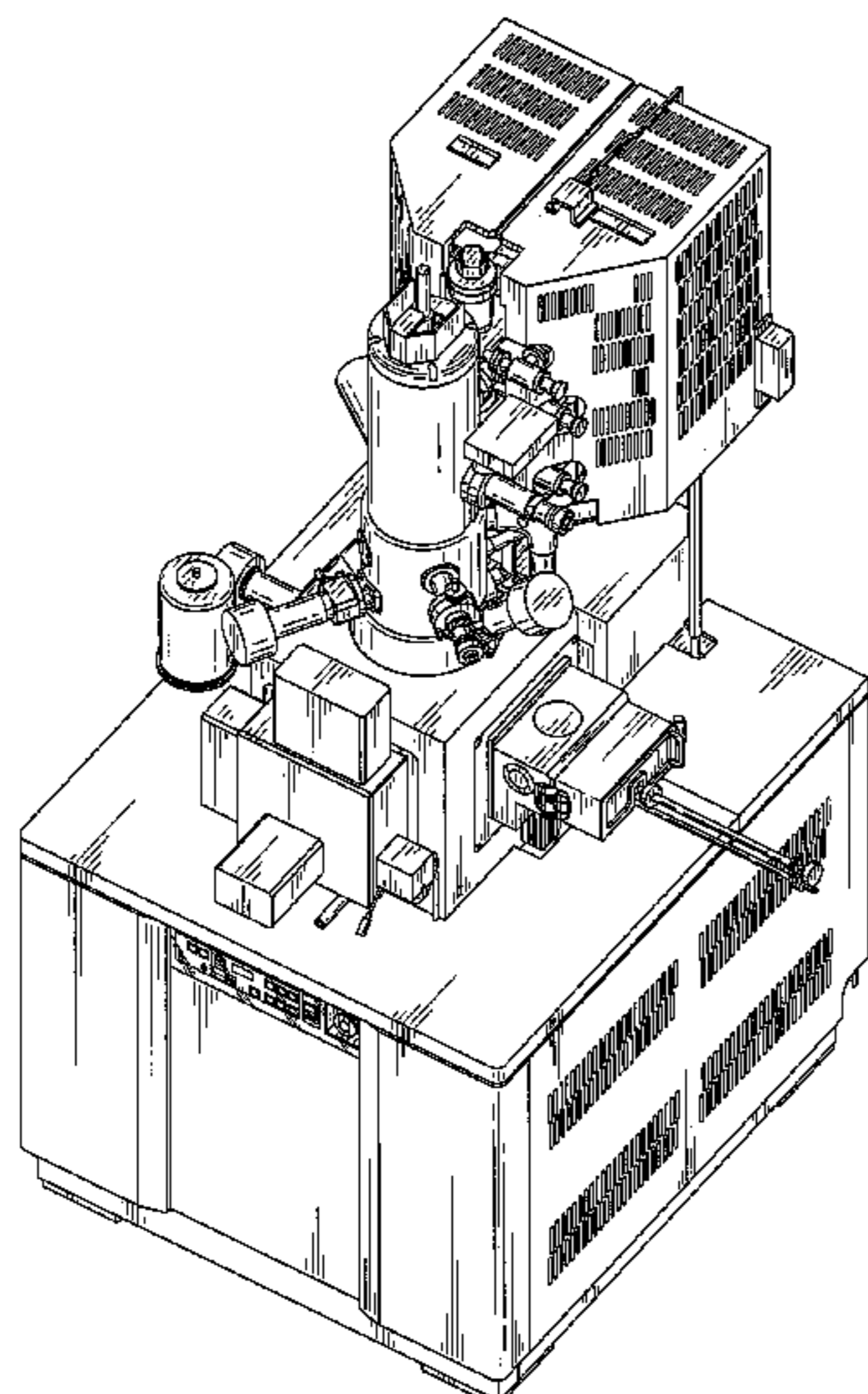
We claim the ornamental design for an electron microscope, as shown and described.

DESCRIPTION

FIG. 1 is a front, top and right side perspective view of an electron microscope showing our new design;
 FIG. 2 is a front elevational view thereof;
 FIG. 3 is a rear elevational view thereof;
 FIG. 4 is a left side elevational view thereof;
 FIG. 5 is a right side elevational view thereof;
 FIG. 6 is a top plan view thereof;
 FIG. 7 is a bottom plan view thereof; and,
 FIG. 8 is an enlarged view of the portion indicated by lines 8 in FIG. 2.

The broken lines of FIG. 8 are for illustrative purposes of the boundaries of the enlarged view and form no part of the claimed design.

1 Claim, 7 Drawing Sheets



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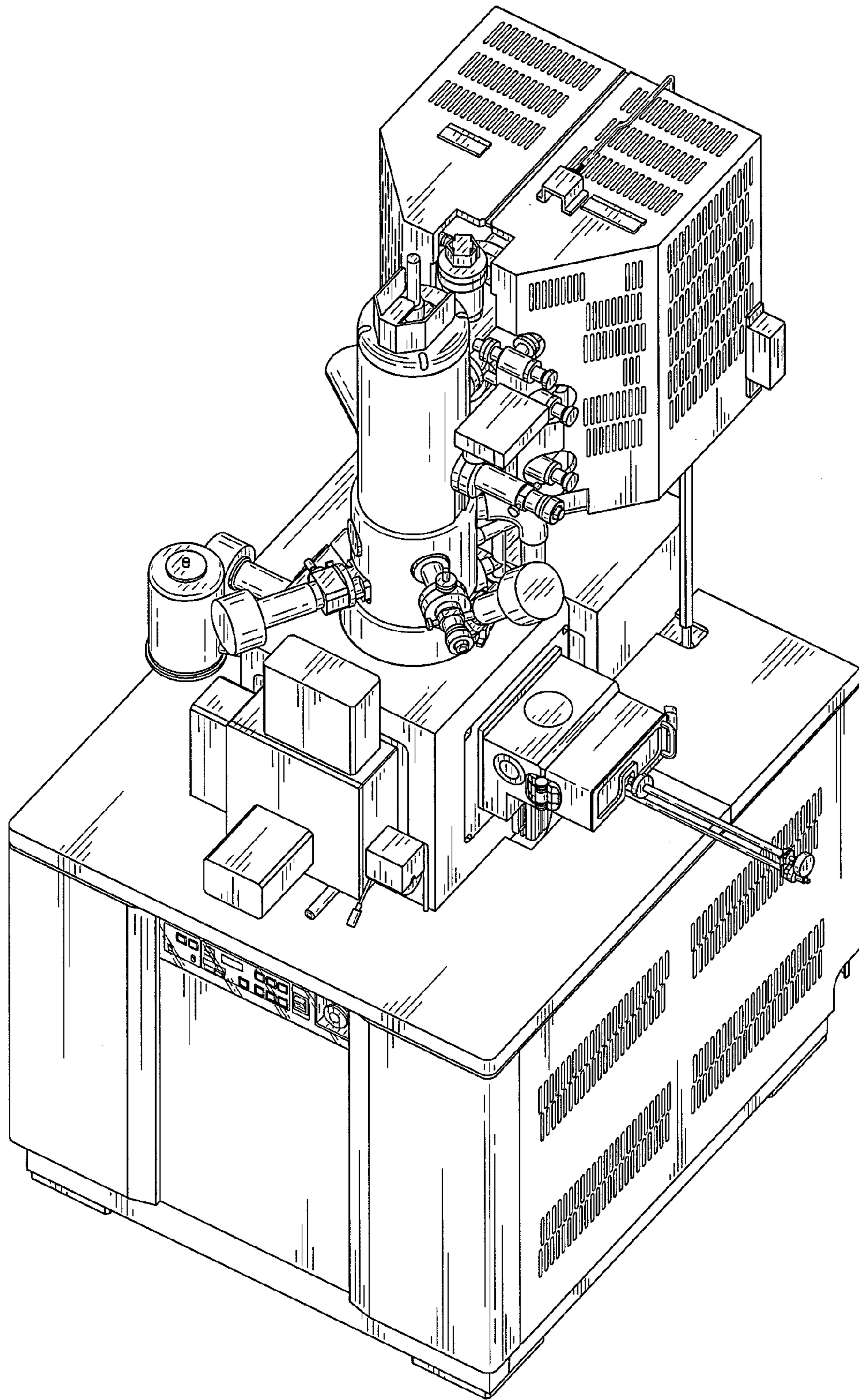


FIG. 1

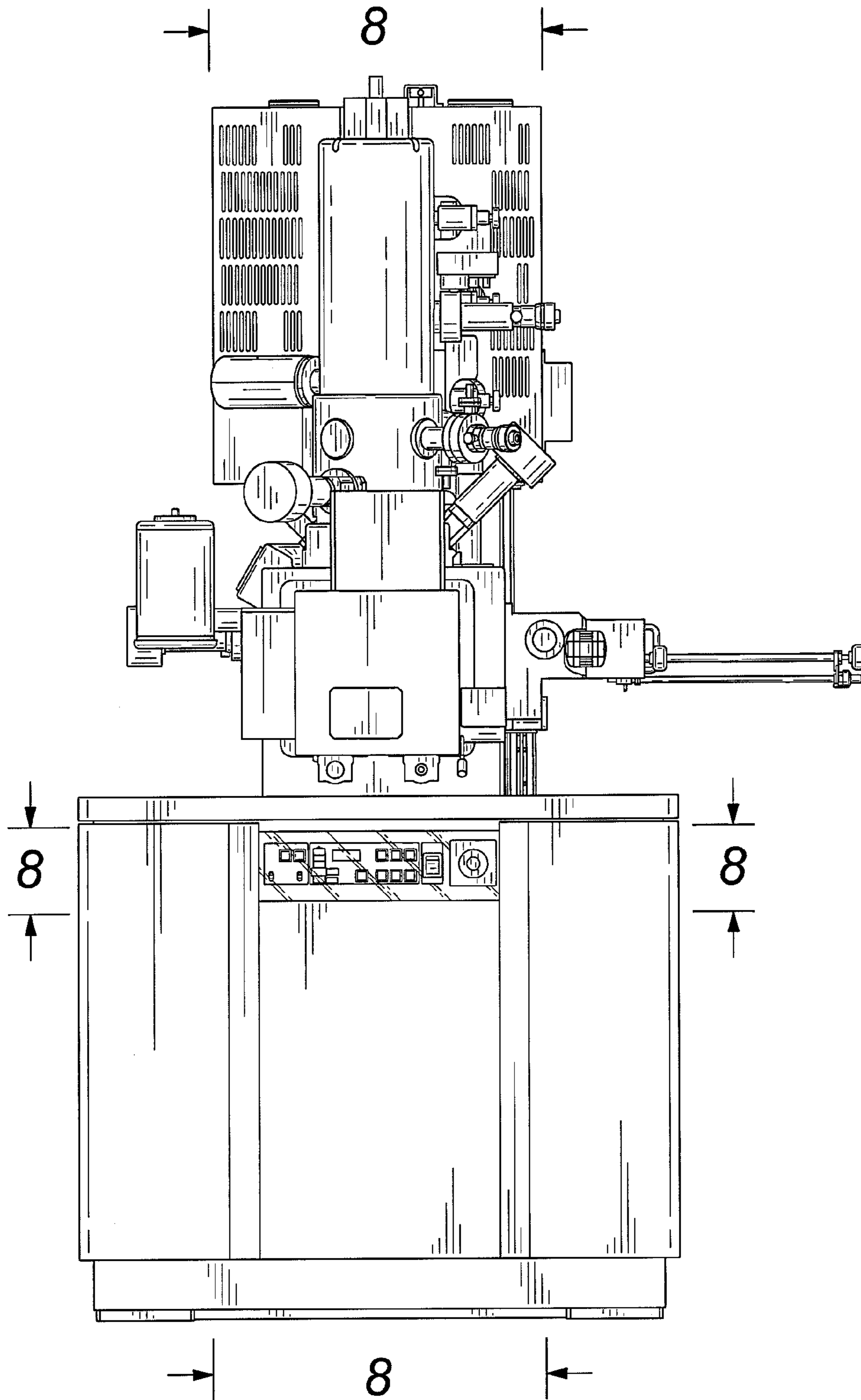


FIG. 2

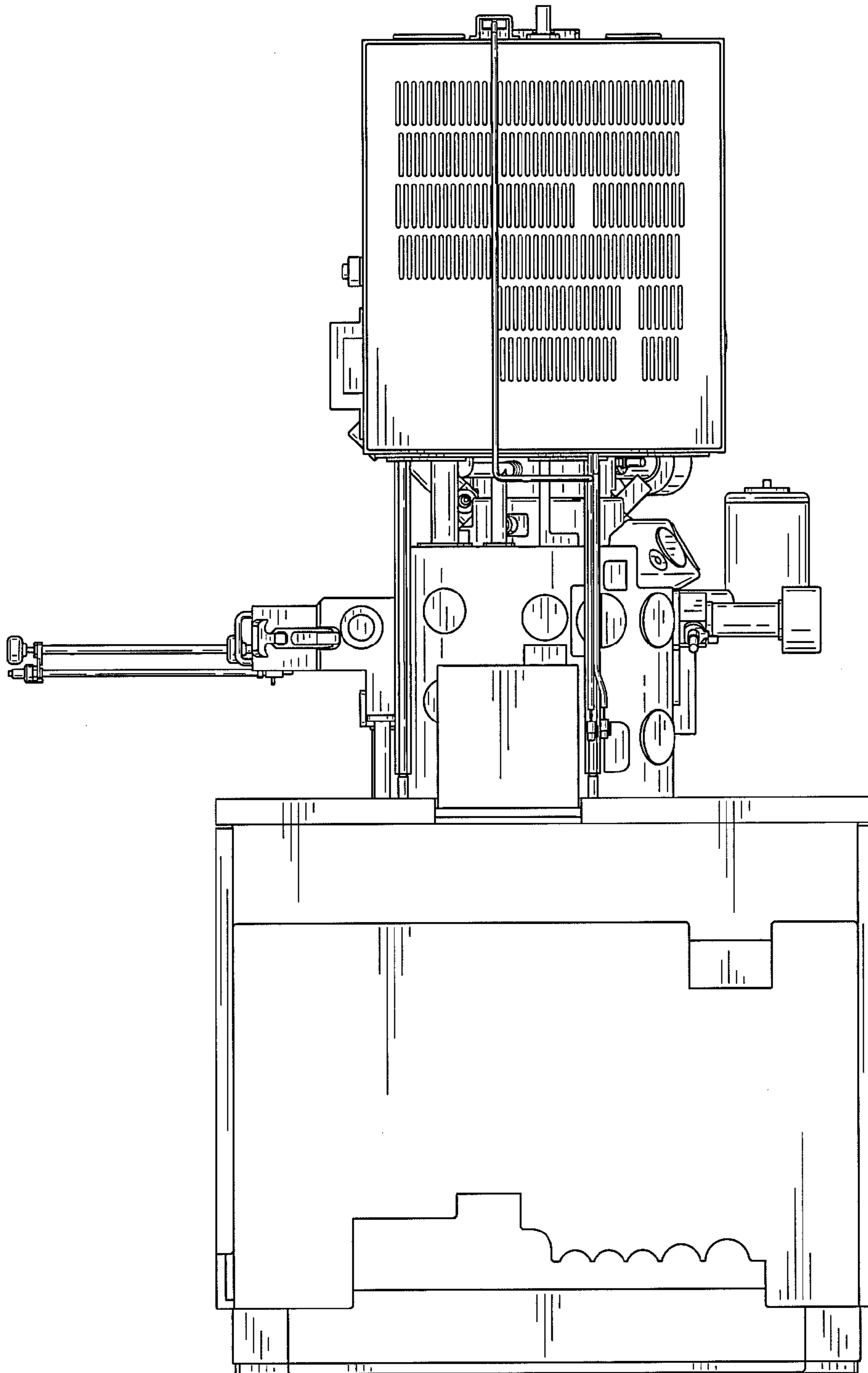


FIG. 3

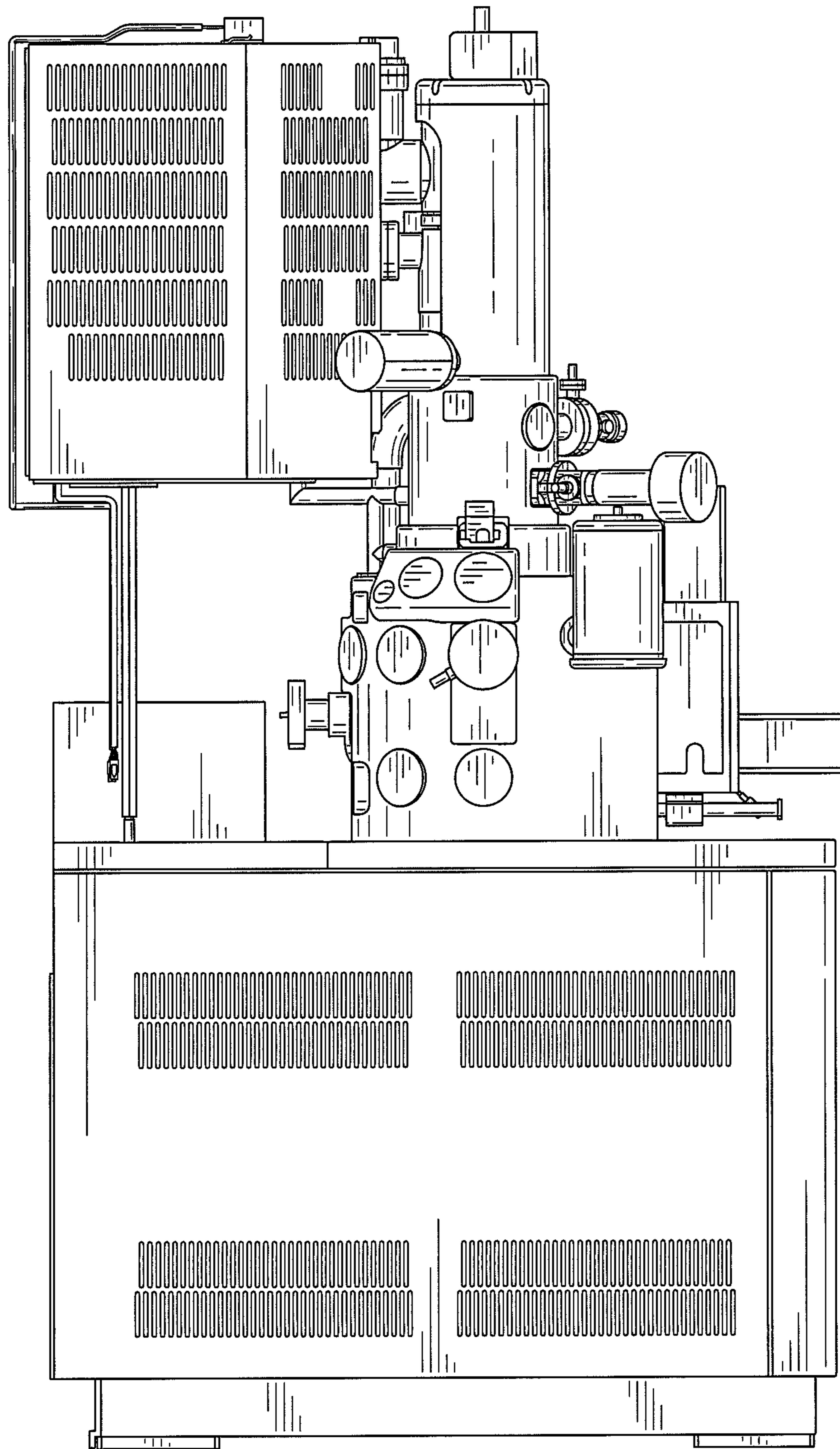


FIG. 4

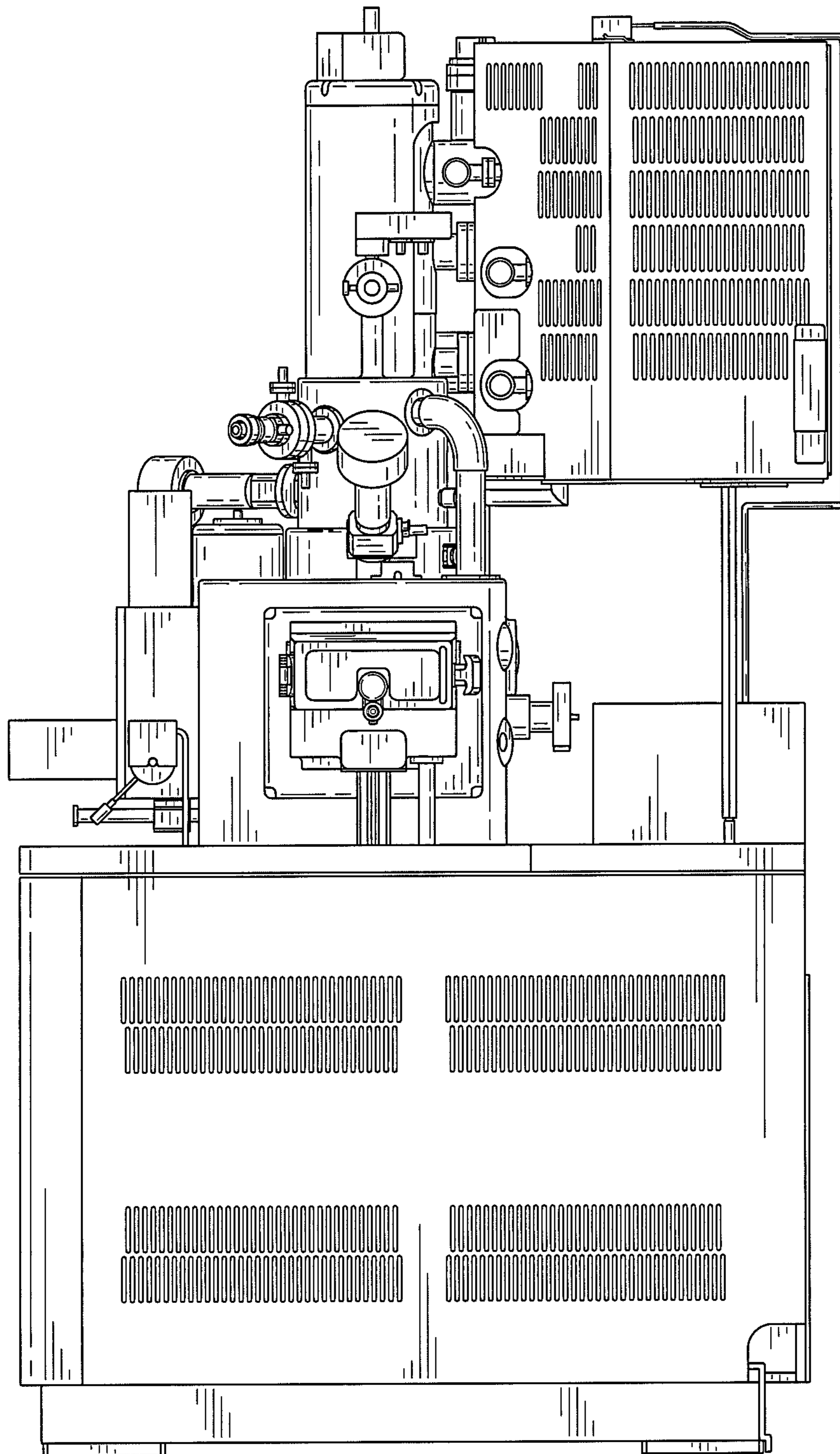


FIG. 5

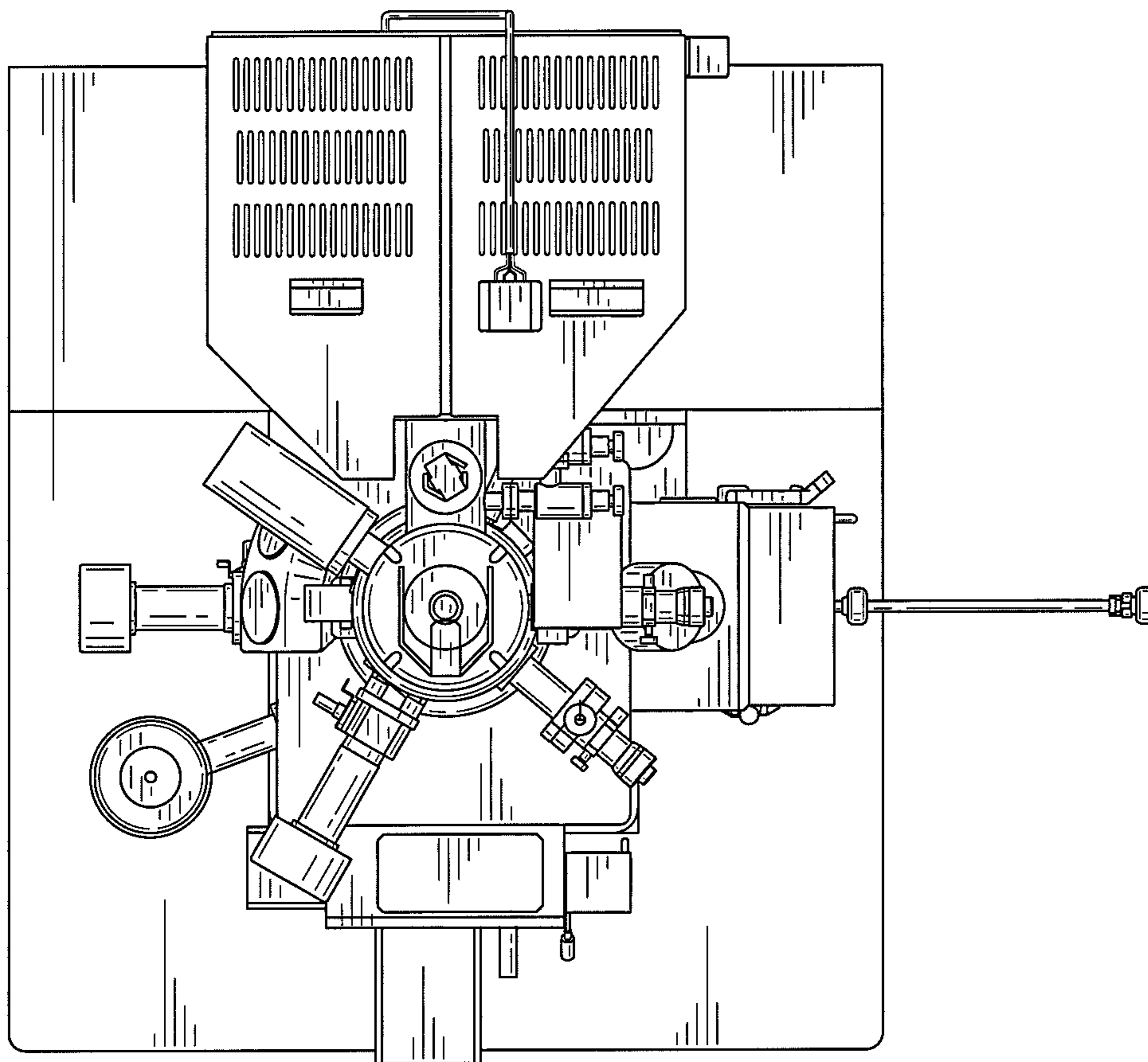


FIG. 6

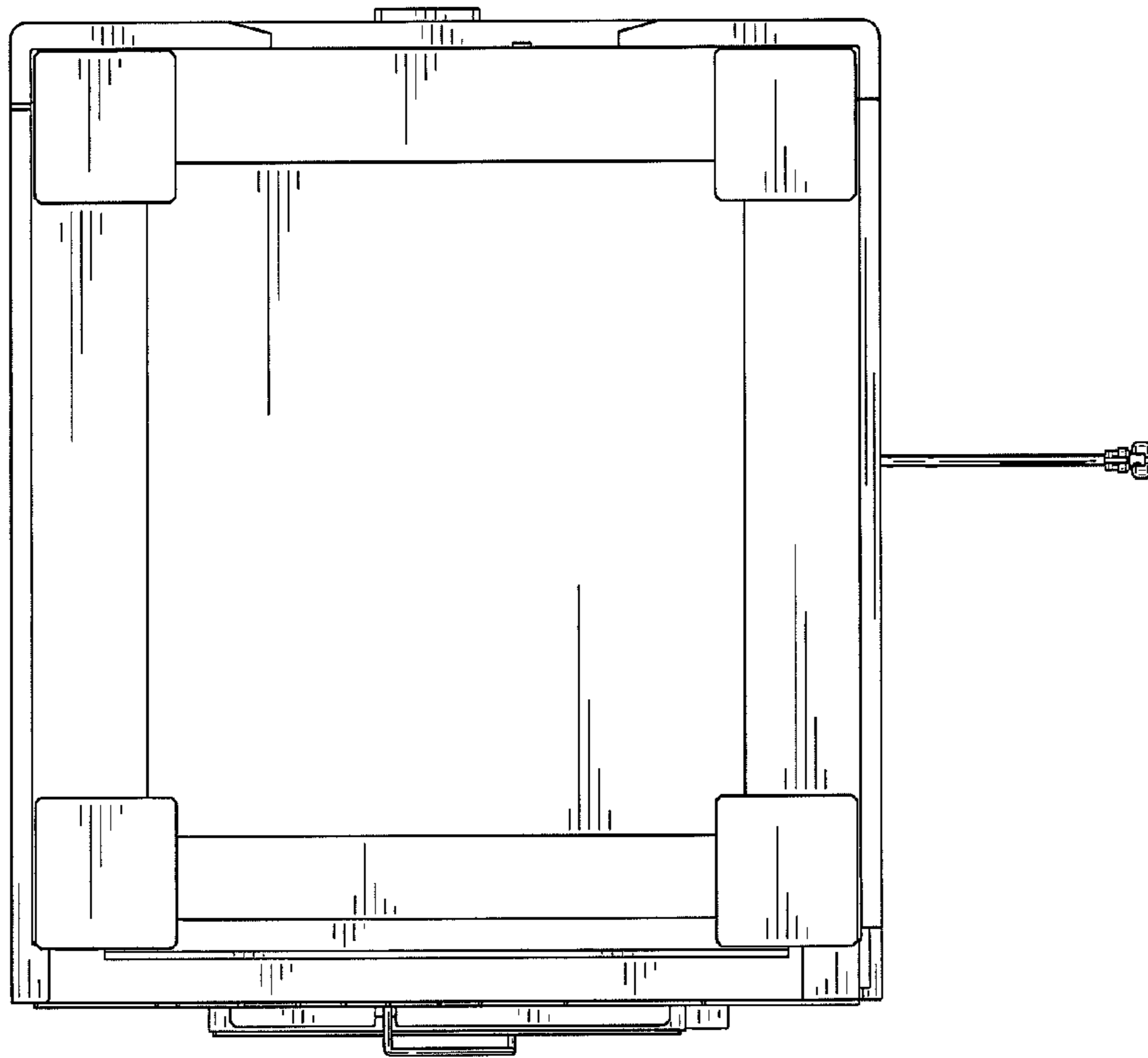


FIG. 7

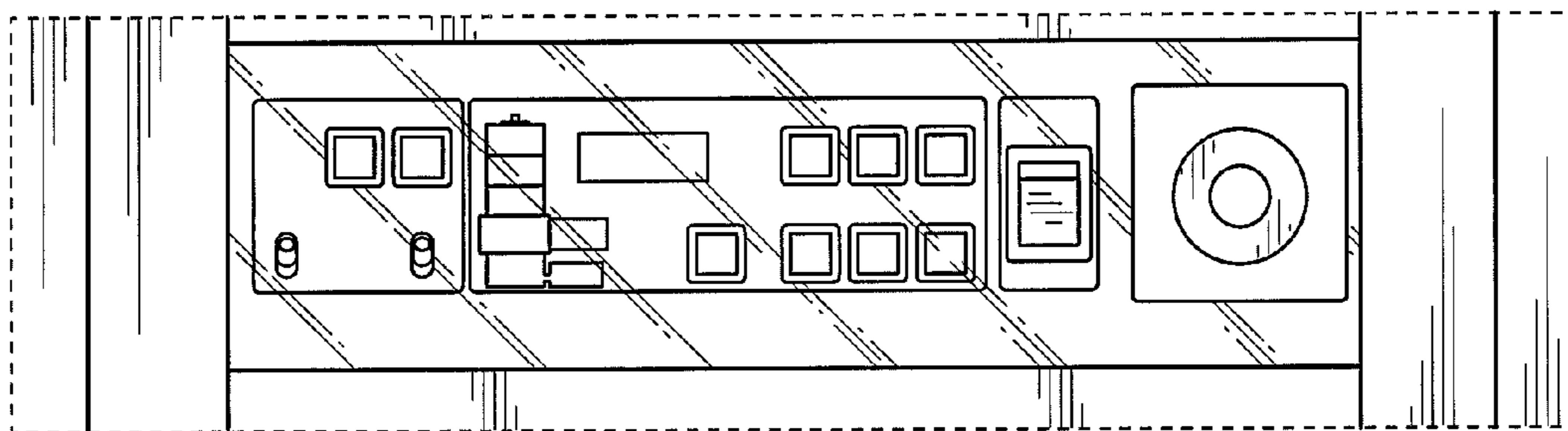


FIG. 8